# **QFET® MOSFET, N-Channel**

400 V, 10.5 A, 530 m $\Omega$ 

### Description

This N-Channel enhancement mode power MOSFET is produced using ON Semiconductor proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.

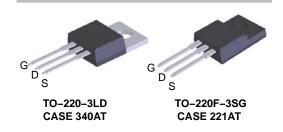
#### **Features**

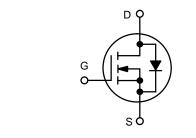
- 10.5 A, 400 V,  $R_{DS(on)} = 530 \text{ m}\Omega$  (Max.) @  $V_{GS} = 10 \text{ V}$ ,  $I_D = 5.25 \text{ A}$
- Low Gate Charge (Typ. 28 nC)
- Low Crss (Typ. 85 pF)
- 100% Avalanche Tested
- These Devices are Pb-Free and are RoHS Compliant



### ON Semiconductor®

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#### **ORDERING INFORMATION**

See detailed ordering, marking and shipping information on page 2 of this data sheet.

#### **ORDERING INFORMATION**

Device	Device Marking	Package	Shipping
FQP11N40C	FQP11N40C	TO-220 (Pb-Free)	1,000 Units / Tube
FQPF11N40C	FQPF11N40C	TO-220 Fullpack, TO-220F-3SG (Pb-Free)	1,000 Units / Tube

### **MOSFET MAXIMUM RATINGS** ( $T_C = 25^{\circ}C$ unless otherwise noted)

Symbol	Parameter		FQP11N40C	FQPF11N40C	Unit
VDSS	Drain to Source Voltage		400		V
ı	Drain Current —Continuous (T <sub>C</sub> = 25°C)		10.5	10.5 *	Α
I <sub>D</sub>	–Continuous (T <sub>C</sub> = 100°C)		6.6	6.6 *	Α
IDM	Drain Current – Pulsed	(Note 1)	42	42 *	Α
Vgss	Gate to Source Voltage		± 30		V
Eas	Single Pulsed Avalanche Energy (Note 2)		36	0	mJ
lar	Avalanche Current (Note 1) 11		I	Α	
Ear	Repetitive Avalanche Energy		13.5		mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4.	4.5	
В	Power Dissipation (T <sub>C</sub> = 25°C)		135	44	W
$P_D$	<ul> <li>Derate above 25°C</li> </ul>		1.07	0.35	W/°C
TJ, TSTG	Operating and Storage Temperature Range		-55 to 150		°C
T <sub>L</sub>	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds		300		°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected. \*Drain current limited by maximum junction temperature 1. Repetitive Rating: Pulse width limited by maximum junction temperature. 2. L = 5.7 mH,  $I_{AS}$  = 10.5 A,  $V_{DD}$  = 50 V,  $V_{DD}$  = 25  $V_{DSS}$ , starting  $V_{DSS}$ , star

### THERMAL CHARACTERISTICS

Symbol	Parameter	FQP11N40C	FQPF11N40C	Unit
$R_{ heta JC}$	Thermal Resistance, Junction to Case, Max	0.93	2.86	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max	62.5	62.5	°C/W

### **ELECTRICAL CHARACTERISTICS** (T<sub>C</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Off Charact	eristics					•
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	400			V
$\Delta BV_{DSS} \ \Delta T_{J}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C		0.54		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 400 V, V <sub>GS</sub> = 0 V			1	μΑ
		$V_{DS} = 320 \text{ V}, T_{C} = 125^{\circ}\text{C}$			10	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	$V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Charact	eristics					
VGS(th)	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2.0		4.0	V
r <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 5.25 A		0.43	0.53	Ω
9FS	Forward Transconductance	V <sub>DS</sub> = 40 V, I <sub>D</sub> = 5.25 A		7.1		s
Dynamic Cl	naracteristics					
Ciss	Input Capacitance	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1 MHz		840	1090	pF
Coss	Output Capacitance	VDS = 23 v, vGS = 0 v, I = 1 WII IZ		250	325	pF
Crss	Reverse Transfer Capacitance			85	110	pF
Switching C	Characteristics					
td(on)				14	40	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 200 \text{ V}, I_D = 10.5 \text{ A}, R_G = 25 \Omega$ (Note 4)		89	190	ns
td(off)	Turn-Off Delay Time	- (Note 4)		81	170	ns
t <sub>f</sub>	Turn-Off Fall Time			81	170	ns
Qg	Total Gate Charge	$V_{DS} = 320 \text{ V}, I_{D} = 10.5 \text{ A}, R_{G} = 25 \Omega$		28	35	nC
Qgs	Gate-Source Charge	(Note 4)		4		nC
Qgd	Gate-Drain Charge	7		15		nC
Orain-Sour	ce Diode Characteristics and Maximum Rati	ngs				
I <sub>S</sub>	Maximum Continuous Drain–Source Diode Forward Current				10.5	А
I <sub>SM</sub>	Maximum Pulsed Drain–Source Diode Forward Current				42	Α
$V_{SD}$	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 10.5 A			1.4	V
trr	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 10.5 A,		290		ns
Qrr	Reverse Recovery Charge	$dI_F/dt = 100 A/\mu s$		2.4		μС

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Essentially independent of operating temperature.

#### TYPICAL PERFORMANCE CHARACTERISTICS

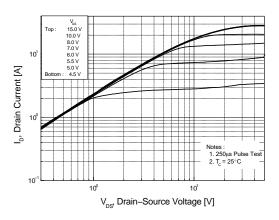


Figure 1. On-Region Characteristics

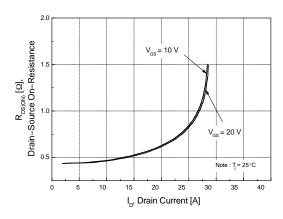


Figure 3. On–Resistance Variation vs Drain Current and Gate Voltage

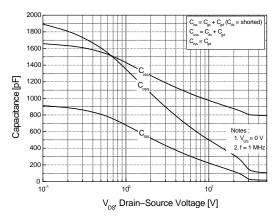


Figure 5. Capacitance Characteristics

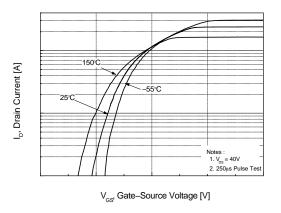


Figure 2. Transfer Characteristics

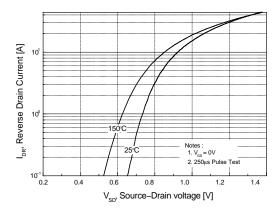


Figure 4. Body Diode Forward Voltage Variation vs.
Source Current and Temperature

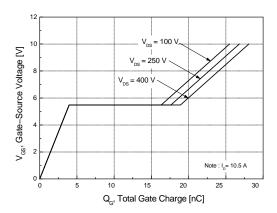


Figure 6. Gate Charge Characteristics

### TYPICAL PERFORMANCE CHARACTERISTICS

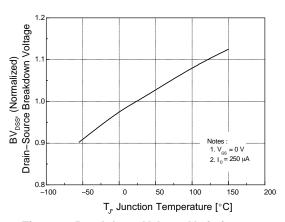


Figure 7. Breakdown Voltage Variation vs.
Temperature

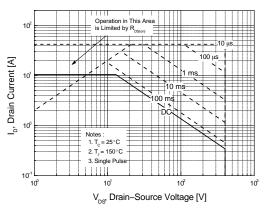


Figure 9. Maximum Safe Operating Area of FQP11N40C

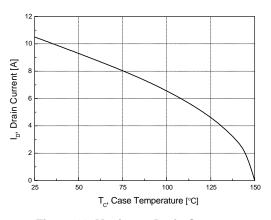


Figure 11. Maximum Drain Current

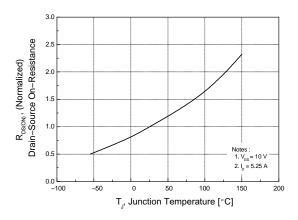


Figure 8. On-Resistance Variation vs. Temperature

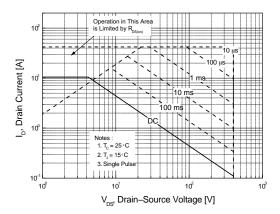


Figure 10. Maximum Safe Operating Area of FQPF11N40C

### TYPICAL PERFORMANCE CHARACTERISTICS

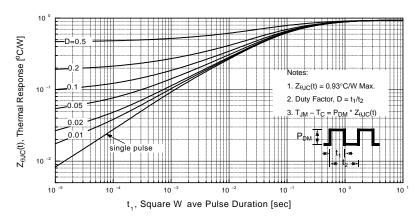


Figure 12. Transient Thermal Response Curve of FQP11N40C

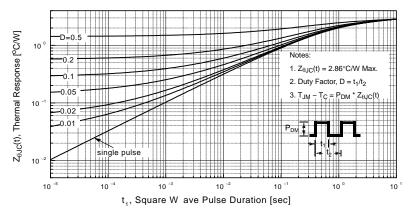


Figure 13. Transient Thermal Response Curve of FQPF11N40C

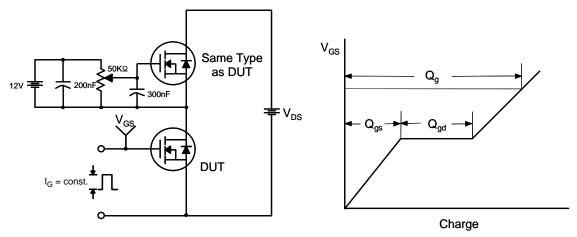


Figure 14. Gate Charge Test Circuit & Waveform

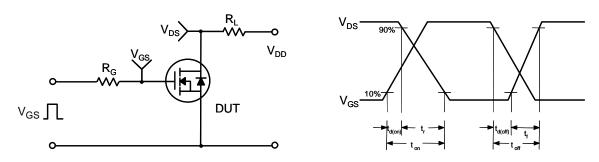


Figure 15. Resistive Switching Test Circuit & Waveforms

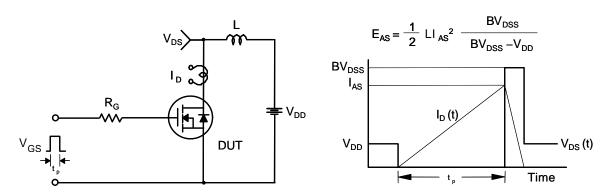
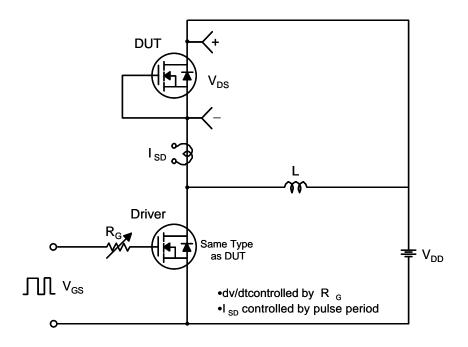


Figure 16. Unclamped Inductive Switching Test Circuit & Waveforms



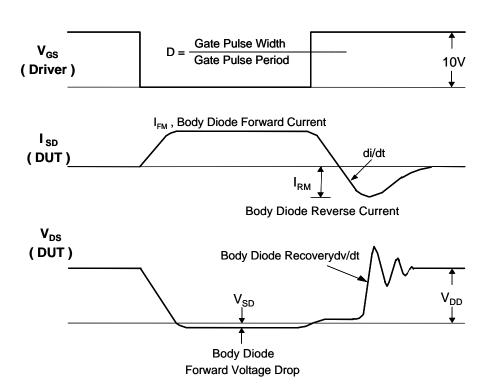
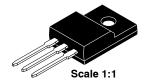


Figure 17. Peak Diode Recovery dv/dt Test Circuit & Waveforms

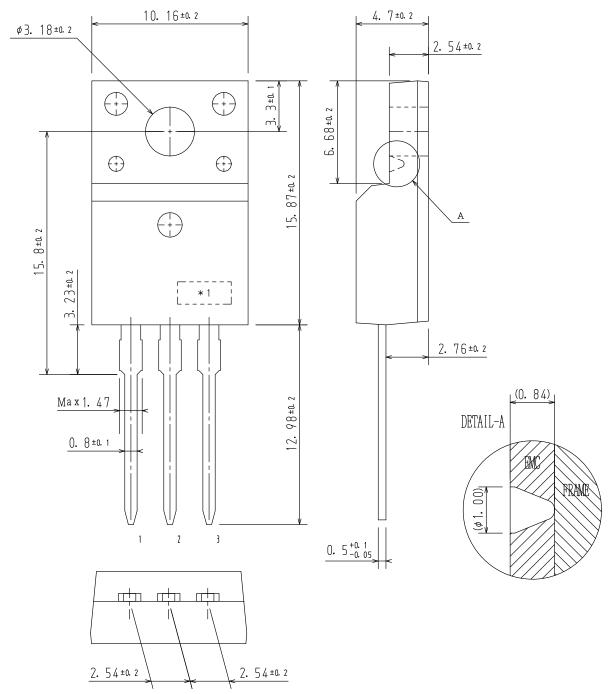
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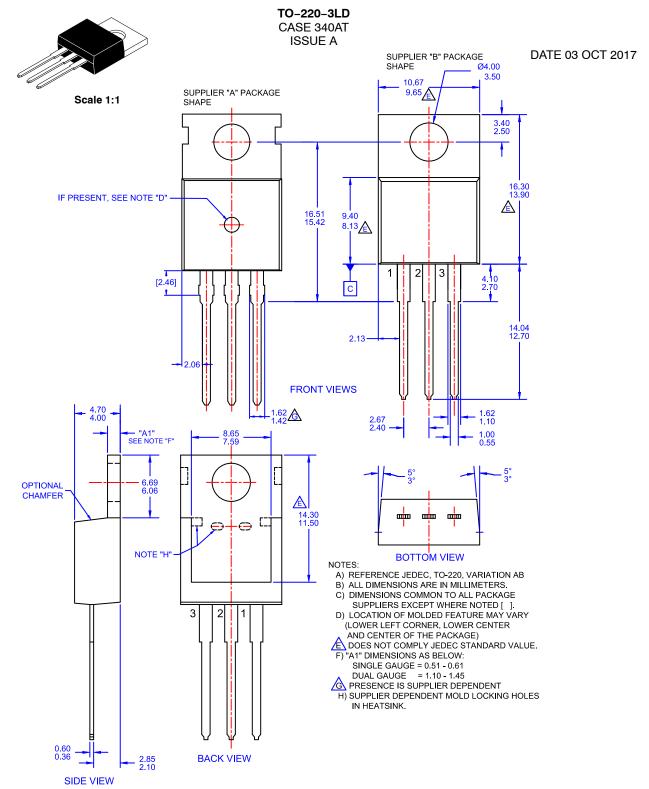
### TO-220 Fullpack, 3-Lead / TO-220F-3SG CASE 221AT ISSUE A

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